
Natalie C. Percy

Applied Research Center College of William and Mary
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EDUCATION

Norfolk State University, Norfolk, Virginia

B.S. Physics, Expected graduation May 2008

Thomas Nelson Community College, Hampton, Virginia

A.S. Science, May 2005

EXPERIENCE

**The College of William and Mary, Applied Research Center Newport News, VA
11/01 – Present**

Laboratory & Research Technician, Materials Characterization Laboratories

Duties Include: Assist with laboratory tours, coordinate gases and technical supplies, process and record purchase orders, perform literature searches, maintain accurate records, collect and statistically analyze data, prepare and deliver results in oral and written presentations, assist with laboratory training of various types of equipment, and provide computer support for all laboratory and office computers located at the W&M ARC.

Ford Motor Company Norfolk, VA 5/00-8/00

Plant Vehicle Team Intern

Duties Included: communicate with suppliers, compile vehicle safety component lists, and review monthly vehicle warranty claims.

SKILLS AND QUALIFICATIONS

Experience in using Time of Flight Secondary Ion Mass Spectrometer, Atomic Force Microscope, Scanning Tunneling Microscope, Surface Profiler, Zeiss Transmitted and Reflective Microscope, Hirox 3D Digital Microscopy, Vickers Micro-Hardness Tester, Scanning Electron Microscope, Energy Dispersive X-Ray Spectroscopy, Variable Angle Ellipsometer, Kelvin Probe, and the Dektak Surface Profiler

CONFERENCES ATTENDED

- 2004**- Materials Research North Carolina Symposium, Research Triangle Park, NC
2004 - Laser Processing Consortium, Jefferson Lab, Newport News, VA Participant
2003 - National Educators' Workshop 2003, Jefferson Lab, Newport News, VA. Poster Presentation.
2002 - 2nd International Workshop on Thin Films, Surfaces and Materials Processing Conference, Jefferson Lab, Newport News, VA. Participant.

CONTINUING EDUCATION

- 2006**- One day on-site training, Hirox Solutions, Hirox 3D digital microscope.
2006- One day on-site training, Digital Instruments, Nanoscope 3100 Scanning Probe Microscope
2005- One day on-site training, Hirox Solutions, Hirox 3D digital microscope.
2005- Five day on-site training, Physical Electronics, Time of Flight SIMS maintenance and operation.
2003 - One day on-site training, Imaque Imaging, Hitachi 570 Scanning Electron Microscope.
2003 - One day on-site training, Digital Electronics, Scanning Tunneling Microscopy.
2003 - One day on-site training, Energy-Dispersive X-Ray Spectroscopy, Thomson Scientific Instruments.
2002 - One day on-site training, Physical Electronics, Time of Flight Secondary Ion Mass Spectrometer.
2002 - One day on-site training, Orion High Resolution Image Grabbing System, Imaque Imaging.
2002 - Two day on-site training, Imaque Imaging, Hitachi 570 Scanning Electron Microscope.
2002 - Three day on-site training, Digital Electronics, Atomic Force Microscope.